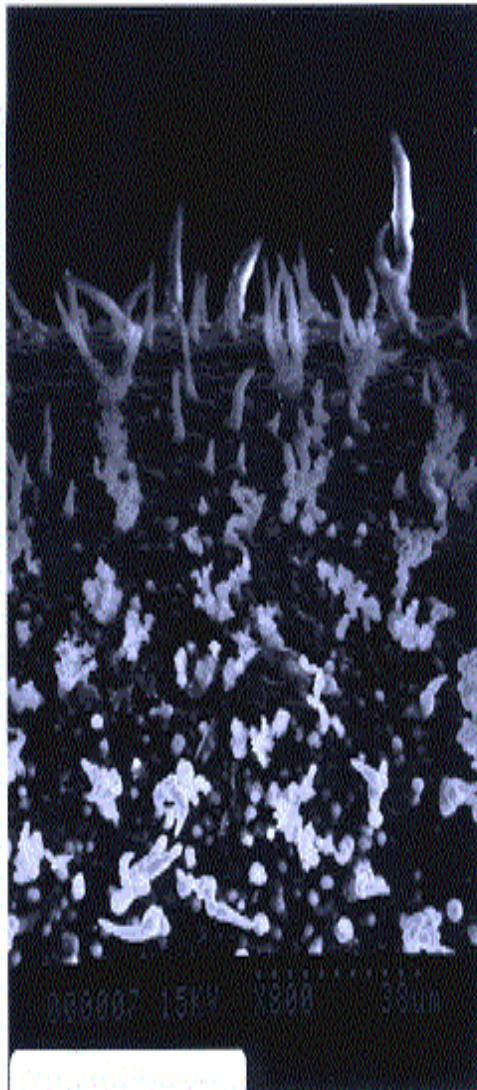


## Effects of Silicon Dioxide Deposition on Ionizing Wires in a Conventional EAC After Two Months



2 month wire

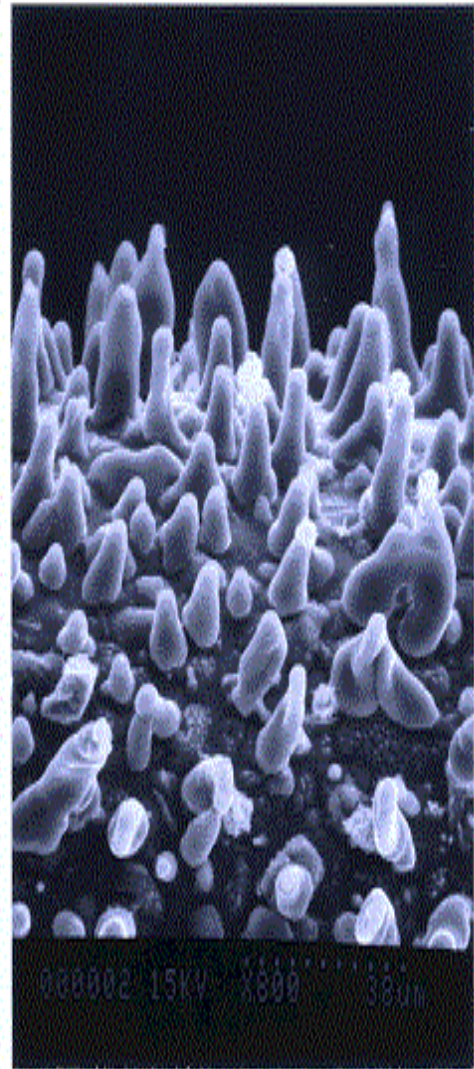


Figure 3. (Left: Real-life; Right: Laboratory Simulation) SEM photomicrographs of an ionizing wire taken from the 2-month real-life ESP (left) and after exposure in the silicone vapor chamber for 19 hours (right). EDX elemental analysis showed all deposits to be silicon based (presumably silicon dioxide).

Image excerpted from “Improved Test Methods for Electronic Air Cleaners”; Fall 2002 issue of *Air Media*. Author(s): JT Hanley; et. al.